

# **Notice of References Cited**

Application/Control No.

10/518,948

Applicant(s)/Patent Under  
Reexamination  
DOU ET AL.

Examiner

Mark Kopec

Art Unit

1796

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* *	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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B	US-			
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E	US-			
F	US-			
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J	US-			
K	US-			
L	US-			
M	US-			

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## **NON-PATENT DOCUMENTS**

* *	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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V	He et al "Reactivity of MgB[sub 2] with common substrate and electronic materials", Applied Physics Letters, 01/14/2002, Vol. 80 Issue 2, p291
W	Jiang et al "Stoichiometry dependence of the critical current density in pure and nano-SiC doped MgB <sub>2</sub> /Fe tapes", Physica C 451(Jan 2007) 71-76
X	Dou et al "Superconductivity, critical current density, and flux pinning in MgB <sub>2</sub> -x(SiC) <sub>x/2</sub> superconductor after SiC nanoparticle doping", Condensed Matter Superconductivity, 4 July 2002, 1-7.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.